



INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification ⁶ : G06K 9/00, A61B 5/117	A1	(11) International Publication Number: WO 98/58342 (43) International Publication Date: 23 December 1998 (23.12.98)
<p>(21) International Application Number: PCT/NO98/00182</p> <p>(22) International Filing Date: 12 June 1998 (12.06.98)</p> <p>(30) Priority Data: 972759 16 June 1997 (16.06.97) NO</p> <p>(71) Applicant (for all designated States except US): SINTEF [NO/NO]; Strindveien 2, N-7034 Trondheim (NO).</p> <p>(72) Inventor; and (75) Inventor/Applicant (for US only): TSCHUDI, Jon [NO/NO]; Brinken 16B, N-0654 Oslo (NO).</p> <p>(74) Agent: ABC-PATENT, SIVILING. ROLF CHR. B. LARSEN A.S; Brynsveien 5, N-0667 Oslo (NO).</p>	<p>(81) Designated States: AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, CA, CH, CN, CU, CZ, DE, DK, EE, ES, FI, GB, GE, GH, GM, GW, HU, ID, IL, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MD, MG, MK, MN, MW, MX, NO, NZ, PL, PT, RO, RU, SD, SE, SG, SI, SK, SL, TJ, TM, TR, TT, UA, UG, US, UZ, VN, YU, ZW, ARIPO patent (GH, GM, KE, LS, MW, SD, SZ, UG, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, ML, MR, NE, SN, TD, TG).</p> <p>Published With international search report. Before the expiration of the time limit for amending the claims and to be republished in the event of the receipt of amendments.</p>	

(54) Title: METHOD AND APPARATUS FOR MEASURING STRUCTURES IN A FINGERPRINT

(57) Abstract

Method and apparatus for the measuring of structures in a fingerprint or the like, comprising the measuring of chosen characteristics of the surface of the fingerprint, e.g. by measuring capacitance or resistivity, using a sensor array comprising a plurality of sensors, being positioned in contact with, or close to, a portion of the surface. The characteristics are measured in at least one line of measuring points along an elongated portion of the surface at given intervals of time, the sensor array being an essentially one-dimensional array, moving the surface in relation to the sensor array in a direction perpendicular to the sensor array, so that the measurements are performed at different, or partially overlapping, portions of the surface, combining the measurements of the measured portions of the surface to provide a segmented, two-dimensional representation of said characteristics of the surface.

